NEOSEM

System Scalability

SX4e-mc

Engineering Lab Chamber Up to 32 Parallel DUTs

SX4-4t1z

1-zone Production Chamber Up to 256 Parallel DUTs

SX4-8t2z

2-zone Production Chamber Up to 512 Parallel DUTs

SX4-16t4z

4-zone Production Chamber Up to 1024 Parallel DUTs

Supported Protocols

- NVMe, AHCI
- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
- SAS 3/6/12 Gbps

Supported Form Factors

- Edge Card (AIC)
 FHFL, FHHL, HHFL, HHHL
- 1.8", 2.5"
- U.2 (Formerly SFF)
- mSATA
- M.2

NEOSEM Technology,Inc

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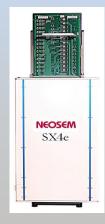
Environmental Mini Chamber SX4e-mc SSD Tester



Full Scalability from Qual to Quantity

The Neosem Technology SX4e-mc Environmental Mini-Chamber provides SSD testing over a wide temperature range in a compact chassis. Designed for SSD reliability and qualification environments, the SX4e-mc combines the production-proven architecture of the SX3 SSD test system with a fully featured chamber that takes up just over 1 square meter of laboratory space for at-temperature testing of up to 32 drives at a time. By utilizing the same tester hardware and software as our larger production chambers, the SX4e-mc allows seamless transition from your engineering lab for reliability testing all the way to your factory floor and High Volume Manufacturing. And like all of the Neosem Technology chamber system, the SX4e-mc also supports Oakgate Technology Storage Verification Framework (SVF) suite to provide industry leading RDT and life testing capabilities.

High Performance Testing



At the heart of the SX4e-mc chamber is the Neosem SX4e+test system, which combines two Core Processor and Protocol Boards, with an Independent Device Power Board to support testing all of the current SSD protocols, and provides the flexibility to adapt to future test needs. The DNA system architecture and infrastructure assures distributed processing, no bandwidth loss, and no signal fidelity loss when scaling from the smallest engineering station to the largest HVM environmental chamber.

SX4e-mc SSD Chamber

Versatile Test Board System

The integrated Test Board (TB) and Tray System from Neosem is a revolutionary transport and test carrier solution specifically designed for manual and automated handling. The Test Boards(TB) are hybrid assemblies of Signal and Power interface boards that are integrated into a durable framework for easy transportation. An EEPROM build on the Test Board stores the test results and can be output to a database. The TB assemblies are compatible with all Neosem's Production and Chamber systems, and they serve to

Chamber systems, and they serve to transport as many as 64 DUTs – and their test results – between test stations.



Customized Integration Solutions

Neosem Technology offers both proven, standardized solutions as well as custom integrated test solutions. Neosem has integrated the SX4 tester hardware into leading Industry's automated handler systems. HVM Environmental chambers are combined with SX4 electronics to allow parallel testing of as many as 1024 DUTs at -10 to 85C. Neosem Technology offers environmental chamber configurations range from one to four independently controlled zones.

SX4e-mc Specifications

Maximum Configuration	32 SATA, 16 SAS , 16(4 Lane PCIe) or 32 (2 Lane M.2)PCIe SSD
Chamber Temperature Range	-10 C to + 85 C
Chamber Condenser	Air Cool Condenser
Chamber Compressor	1 Horse Power (HP)
SX4e+ Tester Hardware	Two SX4 Core Processor(i5) + PCIe Protocol Board, 1 IDP Board
Chamber/Tester Input Power	220V AC – 50 to 60HZ Single Phase
Dimensions(mm)	1050(W) x 1200(D) x 1150(H)
SSD Test Software	Neosem H3/H4 GUI or Optional OakGate SVF Suite

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 - 2-zone Production Chamber Up to 512 Parallel DUTs
- SX4-16t4z
 - 4-zone Production Chamber Up to 1024 Parallel DUTs

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- PCIe 2.0, PCIe 3.0
- SATA 3/6 Gbps
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